

COS/MOS INTEGRATED CIRCUIT

4068 B

HCC/HCF 4068 B

8-INPUT NAND/AND GATE

- MEDIUM-SPEED OPERATION - $t_{PHL}, t_{PLH} = 75$ ns (TYP.) AT 10V
- BUFFERED OUTPUT
- QUIESCENT CURRENT SPECIFIED TO 20V FOR HCC DEVICE
- 5V, 10V, AND 15V PARAMETRIC RATINGS
- INPUT CURRENT OF 100 nA AT 18V AND 25°C FOR HCC DEVICE
- 100% TESTED FOR QUIESCENT CURRENT
- MEETS ALL REQUIREMENTS OF JEDEC TENTATIVE STANDARD No. 13A, "STANDARD SPECIFICATIONS FOR DESCRIPTION OF "B" SERIES CMOS DEVICES"

The **HCC 4068B** (extended temperature range) and **HCF 4068B** (intermediate temperature range) are monolithic integrated circuit, available in 14-lead dual in-line plastic or cerami package, ceramic flat package and plastic micropackage. The **HCC/HCF 4068B** NAND/AND gate provides the system designer with direct implementation of the positive-logic 8-input NAND and AND functions and supplements the existing family of COS/MOS gates.

ABSOLUTE MAXIMUM RATINGS

V_{DD}^*	Supply voltage: HCC types HCF types	-0.5 to 20 -0.5 to 18	V V
V_i	Input voltage	-0.5 to $V_{DD} + 0.5$	V
I_i	DC input current (any one input)	± 10	mA
P_{tot}	Total power dissipation (per package)	200	mW
	Dissipation per output transistor for T_{op} = full package-temperature range	100	mW
T_{op}	Operating temperature: HCC types HCF types	-55 to 125 -40 to 85	°C °C
T_{stg}	Storage temperature	-65 to 150	°C

* All voltage values are referred to V_{SS} pin voltage

ORDERING NUMBERS:

- HCC 4068 BD for dual in-line ceramic package
- HCC 4068 BF for dual in-line ceramic package, frit seal
- HCC 4068 BK for ceramic flat package
- HCF 4068 BE for dual in-line plastic package
- HCF 4068 BF for dual in-line ceramic package, frit seal
- HCF 4068 BM for plastic micropackage

STATIC ELECTRICAL CHARACTERISTICS (over recommended operating conditions)

Parameter		Test conditions				Values						Unit		
		V _I (V)	V _O (V)	I _O (μ A)	V _{DD} (V)	T _{Low} *		25°C			T _{High} *			
						Min.	Max.	Min.	Typ.	Max.	Min.		Max.	
I _L	Quiescent current	HCC types	0/ 5			5		0.25		0.01	0.25		7.5	μ A
			0/10			10		0.5		0.01	0.5		15	
			0/15			15		1		0.01	1		30	
		0/20			20		5		0.02	5		150		
		HCF types	0/ 5			5		1		0.01	1		7.5	
			0/10			10		2		0.01	2		15	
0/15				15		4		0.01	4		30			
V _{OH}	Output high voltage	0/ 5		< 1	5	4.95		4.95			4.95		V	
		0/10		< 1	10	9.95		9.95			9.95			
		0/15		< 1	15	14.95		14.95			14.95			
V _{OL}	Output low voltage	5/0		< 1	5		0.05			0.05		0.05	V	
		10/0		< 1	10		0.05			0.05		0.05		
		15/0		< 1	15		0.05			0.05		0.05		
V _{IH}	Input high voltage		0.5/4.5	< 1	5	3.5		3.5			3.5		V	
			1/9	< 1	10	7		7			7			
			1.5/13.5	< 1	15	11		11			11			
V _{IL}	Input low voltage		4.5/0.5	< 1	5		1.5			1.5		1.5	V	
			9/1	< 1	10		3			3		3		
			13.5/1.5	< 1	15		4			4		4		
I _{OH}	Output drive current	HCC types	0/ 5	2.5		5	-2		-1.6	-3.2		-1.15	mA	
			0/ 5	4.6		5	-0.64		-0.51	-1		-0.36		
			0/10	9.5		10	-1.6		-1.3	-2.6		-0.9		
		0/15	13.5		15	-4.2		-3.4	-6.8		-2.4			
		HCF types	0/ 5	2.5		5	-1.53		-1.36	-3.2		-1.1		
			0/ 5	4.6		5	-0.52		-0.44	-1		-0.36		
0/10	9.5			10	-1.3		-1.1	-2.6		-0.9				
0/15	13.5		15	-3.6		-3.0	-6.8		-2.4					
I _{OL}	Output sink current	HCC types	0/ 5	0.4		5	0.64		0.51	1		0.36	mA	
			0/10	0.5		10	1.6		1.3	2.6		0.9		
			0/15	1.5		15	4.2		3.4	6.8		2.4		
		HCF types	0/ 5	0.4		5	0.52		0.44	1		0.36		
			0/10	0.5		10	1.3		1.1	2.6		0.9		
			0/15	1.5		15	3.6		3.0	6.8		2.4		
I _{IH} , I _{IL}	Input leakage current	HCC types	0/18	Any input	18		+0.1		+10 ⁻⁵	\pm 0.1		+1	μ A	
		HCF types	0/15		15		+0.3		+10 ⁻⁵	\pm 0.3		+1		
C _I	Input capacitance			Any input					5	7.5			pF	

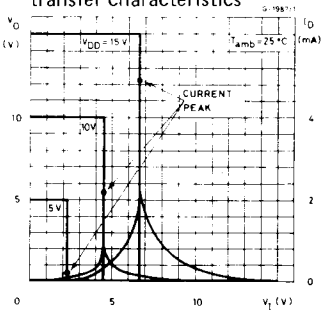
* T_{Low} = - 55°C for HCC device; -40°C for HCF device.
 * T_{High} = +125°C for HCC device; +85°C for HCF device.
 The Noise Margin for both "1" and "0" level is: 1V min. with V_{DD} = 5V
 2V min. with V_{DD} = 10V
 2.5V min. with V_{DD} = 15V

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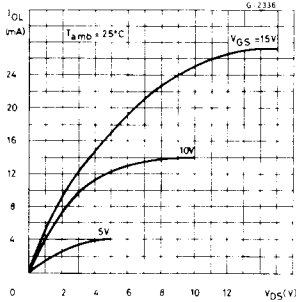
DYNAMIC ELECTRICAL CHARACTERISTICS (T_{amb} = 25°C, C_L = 50 pF, R_L = 200 KΩ, typical temperature coefficient for all V_{DD} values is 0.3%/°C, all input rise and fall times = 20 ns)

Parameter	Test conditions	Values			Unit	
		V _{DD} (V)	Min.	Typ.		Max.
t _{PHL} , t _{PLH} Propagation delay time		5		150	300	ns
		10		75	150	
		15		55	110	
t _{TLH} , t _{THL} Transition time		5		100	200	ns
		10		50	100	
		15		40	80	

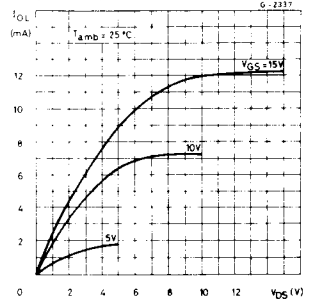
Typical voltage and current transfer characteristics



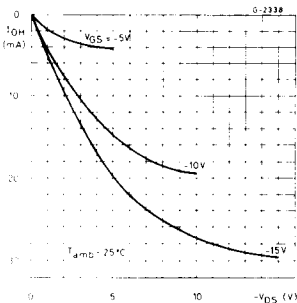
Typical output low (sink) current characteristics



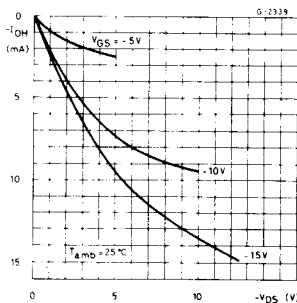
Minimum output low (sink) current characteristics



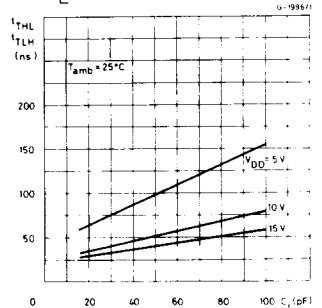
Typical output-p-channel drain characteristics



Minimum output-p-channel drain characteristics

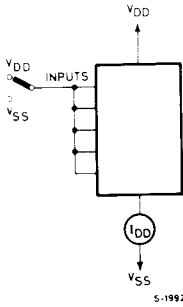


Typical transition time vs. C_L

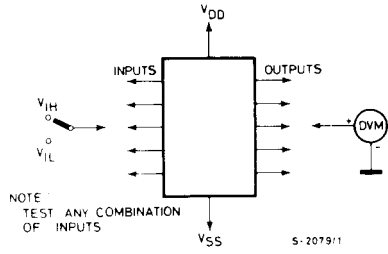


TEST CIRCUITS

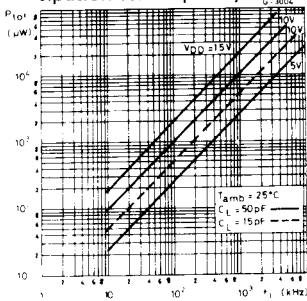
Quiescent device current



Input voltage



Typical dynamic power dissipation vs. frequency



Input current

